

## **AUTOMOTIVE GRADE**

HEXFET® Power MOSFET

## **Features**

- Advanced Planar Technology
- Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching

Description

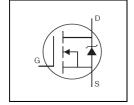
other applications.

- Fully Avalanche Rated
- Repetitive Avalanche Allowed up to Tjmax

Specifically designed for Automotive applications, this Stripe Planar design of HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon

area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are

- Lead-Free, RoHS Compliant
- Automotive Qualified \*



V <sub>DSS</sub>	55V
R <sub>DS(on)</sub> max.	17.5mΩ
I <sub>D</sub>	49A



G	D	S
Gate	Drain	Source

# well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of

Base part number	Packago Typo	Standard Pack		Orderable Part Number
base part number	Package Type	Form	Quantity	Orderable Fait Number
AUIRFZ44N	TO-220	Tube	50	AUIRFZ44N

# **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol Parameter		Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	49	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	35	A
I <sub>DM</sub>	Pulsed Drain Current ①	160	
$P_D @ T_C = 25^{\circ}C$	Power Dissipation	94	W
	Linear Derating Factor	0.63	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ©	150	1
E <sub>AS</sub> (Tested) Single Pulse Avalanche Energy Tested Value ©		530	— mJ
I <sub>AR</sub> Avalanche Current ①		25	А
E <sub>AR</sub> Repetitive Avalanche Energy ①		9.4	mJ
dv/dt	Peak Diode Recovery dv/dt③	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

## **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case		1.5	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

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<sup>\*</sup>Qualification standards can be found at www.infineon.com



# Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.058		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			17.5	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 25A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Trans conductance	19			S	$V_{DS} = 25V, I_{D} = 25A $ ④
	Drain to Source Leakage Current			25	μA	$V_{DS} = 55 \text{ V}, V_{GS} = 0 \text{ V}$
IDSS	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
	Gate-to-Source Forward Leakage			100	n ^	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -20V

# Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	•	• • • • • • • • • • • • • • • • • • • •	•	,		
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$Q_g$	Total Gate Charge	 	63		I <sub>D</sub> = 25A
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$Q_{gs}$	Gate-to-Source Charge	 	14	nC	$V_{DS} = 44V$
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$		Gate-to-Drain Charge	 	23		$V_{GS}$ = 10V , See Fig. 6 and 13
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$t_{d(on)}$	Turn-On Delay Time	 12			$V_{DD} = 28V$
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t <sub>r</sub>	Rise Time	 60			I <sub>D</sub> = 25A
Internal Drain Inductance4.5 Between lead,	$t_{d(off)}$	Turn-Off Delay Time	 44		ns	$R_G = 12\Omega$
	t <sub>f</sub>	Fall Time	 45			V <sub>GS</sub> = 10V, See Fig. 10 ④
nH 6mm (0.25in.)	L <sub>D</sub>	Internal Drain Inductance	 4.5			Between lead, 6mm (0.25in.)
L <sub>S</sub> Internal Source Inductance — 7.5 — Internal Source Inductance and center of die contact	L <sub>S</sub>	Internal Source Inductance	 7.5		ш	
$C_{iss}$ Input Capacitance $-$ 1470 $ V_{GS} = 0V$	$C_{iss}$	Input Capacitance	 1470			$V_{GS} = 0V$
$C_{oss}$ Output Capacitance $\longrightarrow$ 360 $\longrightarrow$ pF $V_{DS} = 25V$	$C_{oss}$	Output Capacitance	 360		pF	$V_{DS} = 25V$
$C_{rss}$ Reverse Transfer Capacitance — 88 — $f = 1.0$ MHz, See Fig. 5		Reverse Transfer Capacitance	 88			f = 1.0MHz, See Fig. 5
E <sub>As</sub> Single pulse Avalanche Energy — 530® 150® mJ I <sub>AS</sub> = 25A, L = 0.47mH		Single pulse Avalanche Energy	 530⑤	150⑥	mJ	I <sub>AS</sub> = 25A, L = 0.47mH

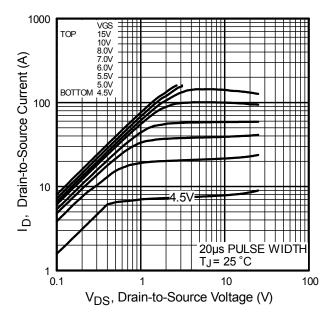
# **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)			49		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			160		integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 25A, V_{GS} = 0V $ ④
t <sub>rr</sub>	Reverse Recovery Time		63	95	ns	$T_J = 25^{\circ}C$ , $I_F = 25A$
Qrr	Reverse Recovery Charge		170	260	nC	di/dt = 100A/µs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsio	turn-or	time is	negligil	ble (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )

# Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting  $T_J = 25^{\circ}C$ , L = 0.48mH,  $R_G = 25\Omega$ ,  $I_{AS} = 25$ A (See fig. 12)
- $\begin{array}{ll} \mbox{ } & I_{SD} \leq 25 \mbox{A, di/dt} \leq \ 230 \mbox{A/\mu s, V}_{DD} \leq \ \mbox{V}_{(BR)DSS}, \ \mbox{T}_{J} \leq 175 \mbox{°C} \\ \mbox{ } & \mbox{Pulse width} \leq 400 \mbox{\mu s; duty cycle} \leq 2\%. \\ \end{array}$
- © This is a typical value at device destruction and represents operation outside rated limits.
- © This is a calculated value limited to  $T_J$  = 175°C.





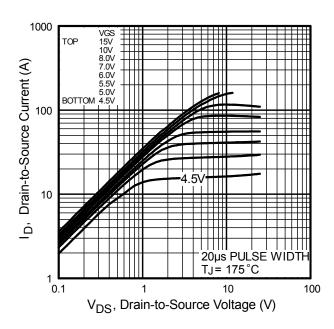
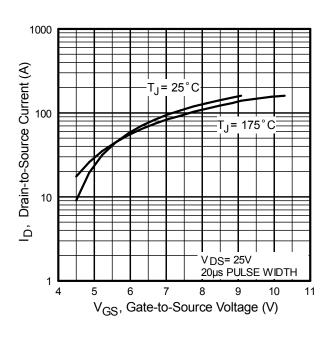
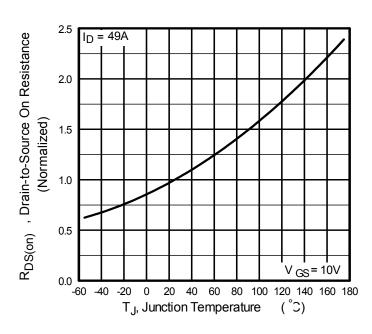


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics



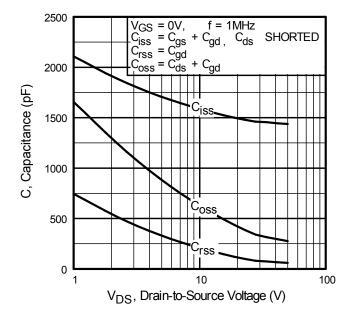




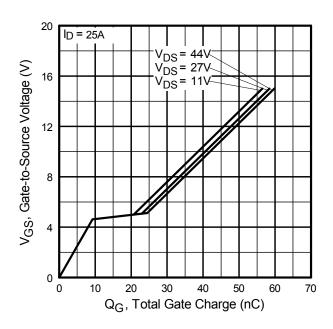
**Fig. 4** Normalized On-Resistance Vs. Temperature

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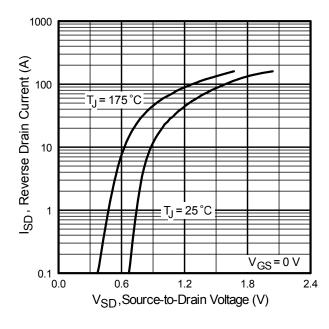




**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage



**Fig. 7.** Typical Source-to-Drain Diode Forward Voltage

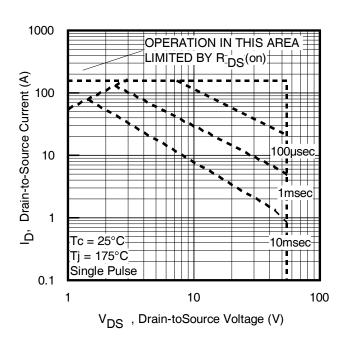


Fig 8. Maximum Safe Operating Area



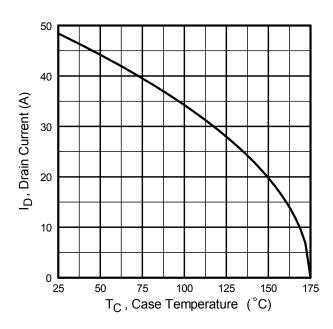


Fig 9. Maximum Drain Current vs. Case Temperature

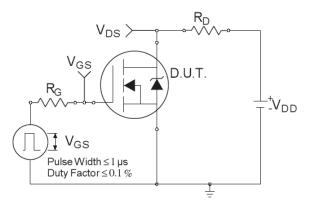


Fig 10a. Switching Time Test Circuit

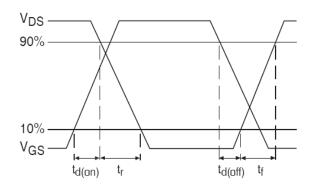


Fig 10b. Switching Time Waveforms

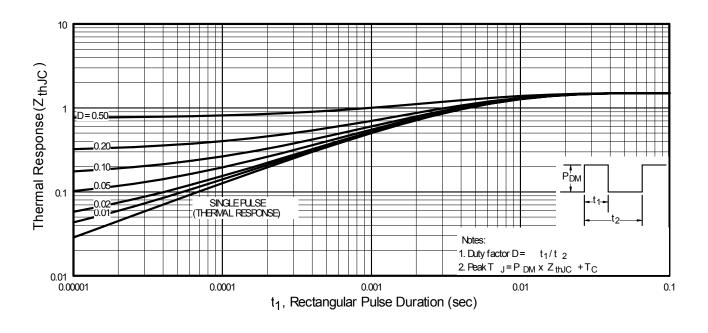


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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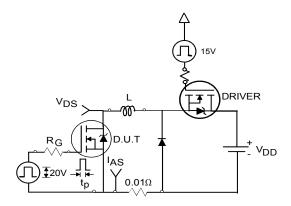


Fig 12a. Unclamped Inductive Test Circuit

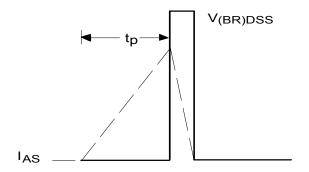


Fig 12b. Unclamped Inductive Waveforms

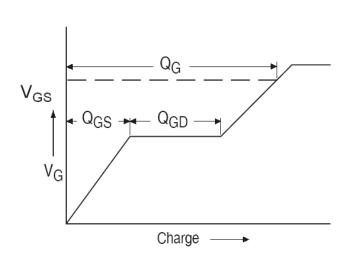
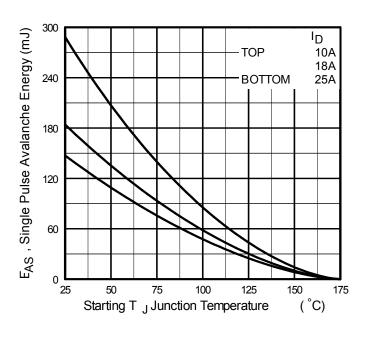


Fig 13a. Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

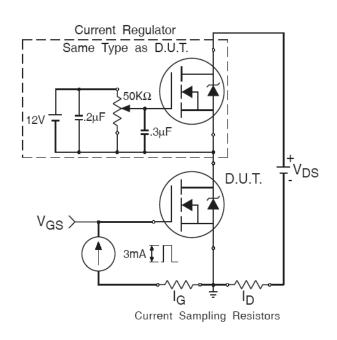
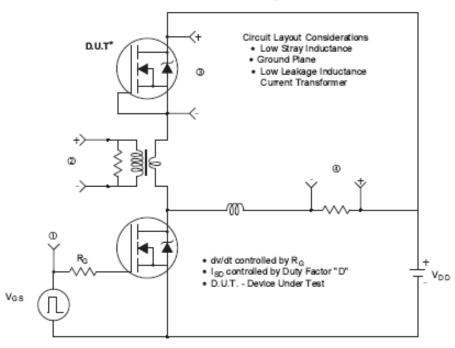


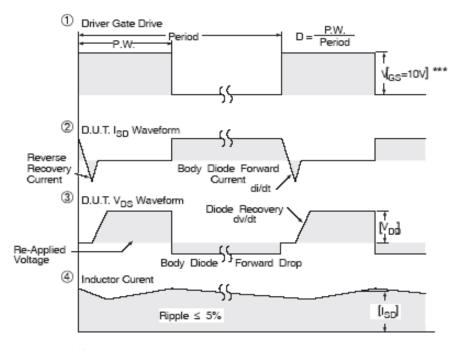
Fig 13b. Gate Charge Test Circuit



# Peak Diode Recovery dv/dt Test Circuit



\* Reverse Polarity of D.U.T for P-Channel

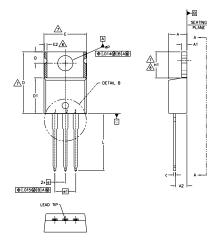


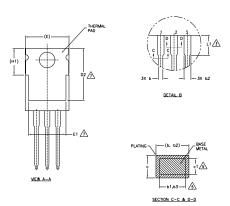
\*\*\* V<sub>GS</sub> = 5.0V for Logic Level and 3V Drive Devices

Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



# TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





#### NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.

- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].

  LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

  DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH
  SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.

- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIMETERS		INC	INCHES		
	MIN.	MAX.	MIN.	MAX.	NOTES	
Α	3.56	4.83	.140	.190		
A1	1,14	1.40	.045	.055		
A2	2.03	2.92	.080	.115		
b	0.38	1.01	.015	.040		
b1	0.38	0.97	.015	.038	5	
b2	1.14	1.78	.045	.070		
b3	1.14	1.73	.045	.068	5	
С	0.36	0.61	.014	.024		
c1	0.36	0.56	.014	.022	5	
D	14.22	16.51	.560	.650	4	
D1	8.38	9.02	.330	.355		
D2	11.68	12.88	.460	.507	7	
E	9.65	10.67	.380	.420	4,7	
E1	6.86	8.89	.270	.350	7	
E2	-	0.76	_	.030	8	
e	2.54	BSC BSC	.100 .200	BSC BSC		
e1	5.08	BSC	.200	BSC		
H1	5.84	6.86	.230	.270	7,8	
L	12.70	14.73	.500	.580		
L1	3.56	4.06	.140	.160	3	
ØΡ	3.54	4.08	.139	.161		
Q	2.54	3.42	.100	.135		

### LEAD ASSIGNMENTS

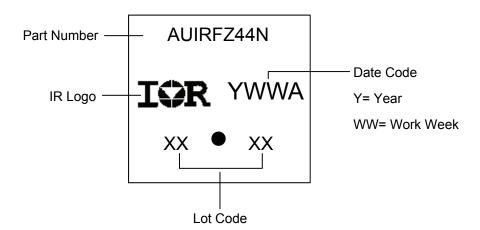
### HEXFET

- 1.- GATE 2.- DRAIN 3.- SOURCE

### IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER
- DIODES
- 1.- ANODE 2.- CATHODE 3.- ANODE

# **TO-220AB Part Marking Information**



TO-220AB package is not recommended for Surface Mount Application.



### **Qualification Information**

<u> </u>	tion iniormation	T					
		Automotive					
		(per AEC-Q101)					
Qualification Level  Comments: This part number(s) passed Automotive qualification.  Industrial and Consumer qualification level is granted by extension of Automotive level.							
Moisture	Sensitivity Level	3L-TO-220AB N/A					
		Class M3 (+/- 400V) <sup>†</sup>					
	Machine Model	AEC-Q101-002					
FOD	Llamana Dada Madal	Class H1C (+/- 1250V) <sup>†</sup>					
ESD	Human Body Model	AEC-Q101-001					
	Channed Davies Madel		Class C5 (+/- 1250V) <sup>†</sup>				
Charged Device Model		AEC-Q101-005					
RoHS Co	mpliant	Yes					
		1					

<sup>†</sup> Highest passing voltage.

# **Revision History**

Date	Comments				
9/25/2017	<ul> <li>Updated datasheet with corporate template.</li> <li>Corrected typo error on package outline and part marking on page 8.</li> </ul>				

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